

CPC**COOPERATIVE PATENT CLASSIFICATION****G01Q****SCANNING-PROBE TECHNIQUES OR APPARATUS; APPLICATIONS OF SCANNING-PROBE TECHNIQUES, e.g. SCANNING PROBE MICROSCOPY [SPM]****NOTE**

In this subclass, the first place priority rule is applied, i.e. at each hierarchical level, classification is made in the first appropriate place.

Guidance heading:

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| G01Q 10/00 | Scanning or positioning arrangements, i.e. arrangements for actively controlling the movement or position of the probe |
| G01Q 10/02 | . Coarse scanning or positioning |
| G01Q 10/04 | . Fine scanning or positioning |
| G01Q 10/045 | . . { Self-actuating probes, i.e. wherein the actuating means for driving are part of the probe itself, e.g. piezoelectric means on a cantilever probe } |
| G01Q 10/06 | . . Circuits or algorithms therefor |
| G01Q 10/065 | . . . { Feedback mechanisms, i.e. wherein the signal for driving the probe is modified by a signal coming from the probe itself } |
| G01Q 20/00 | Monitoring the movement or position of the probe |
| G01Q 20/02 | . by optical means |
| G01Q 20/04 | . Self-detecting probes, i.e. wherein the probe itself generates a signal representative of its position, e.g. piezo-electric gauge |
| G01Q 30/00 | Auxiliary means serving to assist or improve the scanning probe techniques or apparatus, e.g. display or data processing devices |
| G01Q 30/02 | . Non-SPM analysing devices, e.g. SEM [Scanning Electron Microscope], spectrometer or optical microscope |
| G01Q 30/025 | . . { Optical microscopes coupled with SPM } |
| G01Q 30/04 | . Display or data processing devices |
| G01Q 30/06 | . . for error compensation |
| G01Q 30/08 | . Means for establishing or regulating a desired environmental condition within a sample chamber |
| G01Q 30/10 | . . Thermal environment |
| G01Q 30/12 | . . Fluid environment |

G01Q 30/14	...	Liquid environment
G01Q 30/16	..	Vacuum environment
G01Q 30/18	.	Means for protecting or isolating the interior of a sample chamber from external environmental conditions or influences, e.g. vibrations or electromagnetic fields
G01Q 30/20	.	Sample handling device or method
G01Q 40/00		Calibration, e.g. of probes
G01Q 40/02	.	Calibration standards and methods of fabrication thereof
G01Q 60/00		Particular type of SPM [Scanning Probe Microscopy] or microscopes; Essential components thereof
G01Q 60/02	.	Multiple-type SPM, i.e. involving more than one SPM technique
G01Q 60/04	..	STM [Scanning Tunnelling Microscopy] combined with AFM [Atomic Force Microscopy]
G01Q 60/06	..	SNOM [Scanning Near-field Optical Microscopy] combined with AFM [Atomic Force Microscopy]
G01Q 60/08	..	MFM [Magnetic Force Microscopy] combined with AFM [Atomic Force Microscopy]
G01Q 60/10	.	STM [Scanning Tunnelling Microscopy] or apparatus therefor, e.g. STM probes
G01Q 60/12	..	STS [Scanning Tunnelling Spectroscopy]
G01Q 60/14	..	STP [Scanning Tunnelling Potentiometry]
G01Q 60/16	..	Probes, their manufacture, or their related instrumentation, e.g. holders
G01Q 60/18	.	SNOM [Scanning Near-Field Optical Microscopy] or apparatus therefor, e.g. SNOM probes
G01Q 60/20	..	Fluorescence
G01Q 60/22	..	Probes, their manufacture, or their related instrumentation, e.g. holders
G01Q 60/24	.	AFM [Atomic Force Microscopy] or apparatus therefor, e.g. AFM probes
G01Q 60/26	..	Friction force microscopy
G01Q 60/28	..	Adhesion force microscopy
G01Q 60/30	..	Scanning potential microscopy
G01Q 60/32	..	AC mode
G01Q 60/34	...	Tapping mode
G01Q 60/36	..	DC mode
G01Q 60/363	...	{ Contact-mode AFM }
G01Q 60/366	...	{ Nanoindenters, i.e. wherein the indenting force is measured }
G01Q 60/38	..	Probes, their manufacture, or their related instrumentation, e.g. holders
G01Q 60/40	...	Conductive probes
G01Q 60/42	...	Functionalization
G01Q 60/44	.	SICM [Scanning Ion-Conductance Microscopy] or apparatus therefor, e.g. SICM probes

G01Q 60/46	. SCM [Scanning Capacitance Microscopy] or apparatus therefor, e.g. SCM probes
G01Q 60/48	.. Probes, their manufacture, or their related instrumentation, e.g. holders
G01Q 60/50	. MFM [Magnetic Force Microscopy] or apparatus therefor, e.g. MFM probes
G01Q 60/52	.. Resonance
G01Q 60/54	.. Probes, their manufacture, or their related instrumentation, e.g. holders
G01Q 60/56	... Probes with magnetic coating
G01Q 60/58	. SThM [Scanning Thermal Microscopy] or apparatus therefor, e.g. SThM probes
G01Q 60/60	. SECM [Scanning Electro-Chemical Microscopy] or apparatus therefor, e.g. SECM probes
G01Q 70/00	General aspects of SPM probes, their manufacture or their related instrumentation, insofar as they are not specially adapted to a single SPM technique covered by group G01Q 60/00
G01Q 70/02	. Probe holders
G01Q 70/04	.. with compensation for temperature or vibration induced errors
G01Q 70/06	. Probe tip arrays
G01Q 70/08	. Probe characteristics
G01Q 70/10	.. Shape or taper
G01Q 70/12	... Nano-tube tips
G01Q 70/14	.. Particular materials
G01Q 70/16	. Probe manufacture
G01Q 70/18	.. Functionalization
G01Q 80/00	Applications, other than SPM, of scanning-probe techniques (manufacture or treatment of nano-structures B82B 3/00; recording or reproducing information using near-field interaction G11B 9/12, G11B 11/24, G11B 13/08)
G01Q 90/00	Scanning-probe techniques or apparatus not otherwise provided for